ShibaSoku®

S230 Series

PDP Driver IC Test System

Automated Test Equipment

Overview

The S230 test system has been specially designed for testing PDP (Plasma display) driver devices and has been a de-fact standard in the PDP Driver testing market.
This system can be used to test both data driver and high voltage scan driver device testing.
Moreover, its test head is easy to dock to a TCP handler, pick & place handler and wafer prober, so that the S230 can be used for mass production wafer probe and package tests.

Features

- Max. 512 pins (128 I/O pins + 384 High voltage pins)
- Max. 4 devices in parallel test
- High voltage DC measurement (250 V) with HVPMU for scan driver ICs
- Over current protection to prevent pin electronics damage from device circuit short

Specifications

Digital I/O pin	Max. 128 pins (-2 to +8 V)
High voltage pin	Max. 384 pins (125/250 V range) (Comparator pins)
Functional test	20/40/60 MHz Test Rate (RSDS: 83.3 MHz)
DC voltmeter	2 inputs +/-32 V max.(Single, direct input) +/-64 V max.(Diff., direct input) +/-512 V max.(Diff., ATT. input)
V/I source	+/-128 V, +/-250 mA (+/-40 V, +/-2 A)
High voltage source (HVS)	-5 to +250 V, +/- 400 mA (+/-800 mA by parallel connection)
High voltage measurement unit (HVPMU)	-5 to +250 V, +/-32 mA
Parallel test capability	1/2/4 DUTs

Target Devices

PDP Driver ICs (Data Driver & Scan Driver)

ShibaSoku Co., Ltd.

● International ATE Sales Dept.

848 Wakamatsu-cho, Tokorozawa-shi, Saitama,
359-0032, Japan

Phone; +81-4-2996-3411 Fax; +81-4-2996-3419

Mail to; info@shibasoku.co.jp
URL; http://www.shibasoku.com